## Notice of References Cited Application/Control No. O9/994,809 Examiner A. Sefer Applicant(s)/Patent Under Reexamination YOO ET AL. Art Unit Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-6,414,730	07-2002	Akamatsu et al.	349/43
	В	US-6,407,780	06-2002	Sung, Chae Gee	349/43
	С	US-2003/0067038	04-2003	Fujikawa et al.	257/347
	D	US-6,218,221	04-2001	Sah, Wen-Jyh	438/158
	E	US-6,528,357	03-2003	Dojo et al.	438/151
	F	US-			
	G	US-			
	Н	US-			
	1	US-			
	J	US-			
	К	US-			
	L	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 2000-199917	07-2000	Japan	Akamatsu et al.	
	0					
	Р					
	Q					
	R					
	s					
	Т					

## NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)				
	U					
	٧					
	w					
	х					

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.